

## Si-Photonics iSiPP50G

| Modules                           | Description  | Enabled devices  |
|-----------------------------------|--|--|
| 3 silicon patterning steps        | 3 etch depths in 220nm Si:<br>70nm, 160nm;<br>220nm (193 nm litho)         | Strip/rib waveguides,<br>various passive optical devices,<br>silicon taper                                     |
| Gate oxide and Poly-Silicon layer | 1 etch depth:<br>full poly etch (160nm)<br>(193nm litho)                   | Advanced grating couplers,<br>poly-Si waveguide  |
| Ion implantation in Si            | 8 implants levels:<br>4x n-type and<br>4x p-type                           | Si carrier depletion,<br>injection and accumulation<br>devices,<br>Ge Photodectors,<br>doped Si resistors, ... |
| Ge module                         | 100% Ge(Si) RPCVD<br>selective epitaxial<br>growth & 2x<br>implants levels | Ge Photodectors<br>Ge(Si) EA modulator   |
| Silicide tungsten contact module  | Ohmic contacts<br>to doped silicon   | Standard CMOS<br>contacts plugs  |
| Metal heater                      | Metal layer for heaters  | Metal heaters  |
| Two-level metal interconnect      | Cu-based two-level<br>metallization  | Standard CMOS<br>interconnects   |
| Aluminium passivation             | Aluminium finish<br>metallization  | Standard CMOS<br>interconnects   |
| Deep trench                       | Deep trench<br>to expose edge<br>coupler facets                            | Edge couplers  |